

Search Notes

Application/Control No.

10/685,473

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

KLEIN, MARTIN G.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	122	2/22/2007	DWY
429	128	2/22/2007	DWY
429	142	2/22/2007	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
429	122	2/22/2007	DWY
429	128	2/22/2007	DWY
429	142	2/22/2007	DWY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/22/2007	DWY
Inventorship Search	2/22/2007	DWY